



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of: Satya et al.

Attorney Docket No.: KLA1P016G

Application No.: 09/648,381

Examiner: Andre Stevenson C.

Filed: August 25, 2000

Group: 2812

Title: MULTI-PIXEL METHODS AND  
APPARATUS FOR ANALYSIS OF  
DEFECT INFORMATION FROM TEST  
STRUCTURES ON SEMICONDUCTOR  
DEVICES

**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first-class mail on December 22, 2003 in an envelope addressed to the Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450.

Signed: \_\_\_\_\_

Natalie Morgan

**SEPARATE LETTER TO THE OFFICIAL DRAFTSMAN  
REQUESTING ENTERING OF FORMAL DRAWINGS  
(MPEP 608.02(p))**

Mail Stop Issue Fee  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In response to the objections made due to informalities in the original drawings (or to corrections approved by the Examiner), enclosed are substitute (formal) drawings for the above-identified patent application. If the Draftsman has any question concerning these drawings, he or she is respectfully requested to contact the undersigned.

Respectfully submitted,  
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